



US CMS EMU meeting

Anode Front-End electronics status.

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Anode Front-End electronics status

- AFEB production status
 - CMP16-G ASIC
 - AFEB production
 - AFEB certification
 - AFEB shipment
- Documentation
- AFEB-ALCT cable production
- Delay chip DEL16 test status



AFEB production status

CMP16_G ASIC

- Produced quantity 25,000
- Tested 16,500
- Selected for soldering for US 13,300
- sent to Dubna 1,472
- Yield rate 90%

We have to test more 8,500 chips

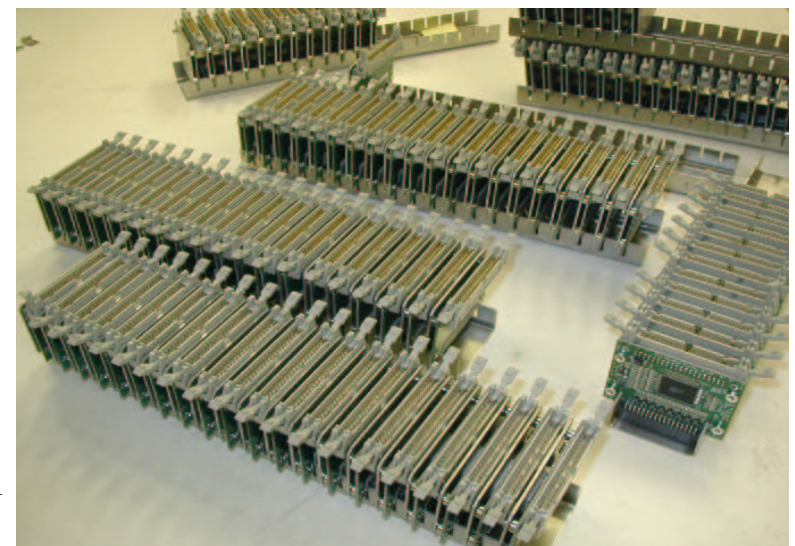


AFEB production display

	CY2001					CY2002												Made	Total needed	Balance	Shipped out.	Total at FNAL															
	prev.	Sep.	Oct.	Nov.	Dec.	Jan.	Feb.	Mar.	Apr.	May	Jun.	Jul.	Aug.	Sep.	Oct.	Nov.	Dec.																				
Delivered to FNAL	1109			747	2446																																
Burned in		250	800	1200	1600	1800	1400	1800	1200		400																										
Assembled		250		580	1500	398	1879	2117																													
Tested		250		580	1500	255	1709	1894																													
Packaged			248			1008	1074	3636																													
Shipped to:																																					
UF			124				539			360																											
UCLA			124				535			360																											
PNPI						1008		1152																													
IHEP/flat								720																													
IHEP/tray								864																													
Total shipped out:																																					

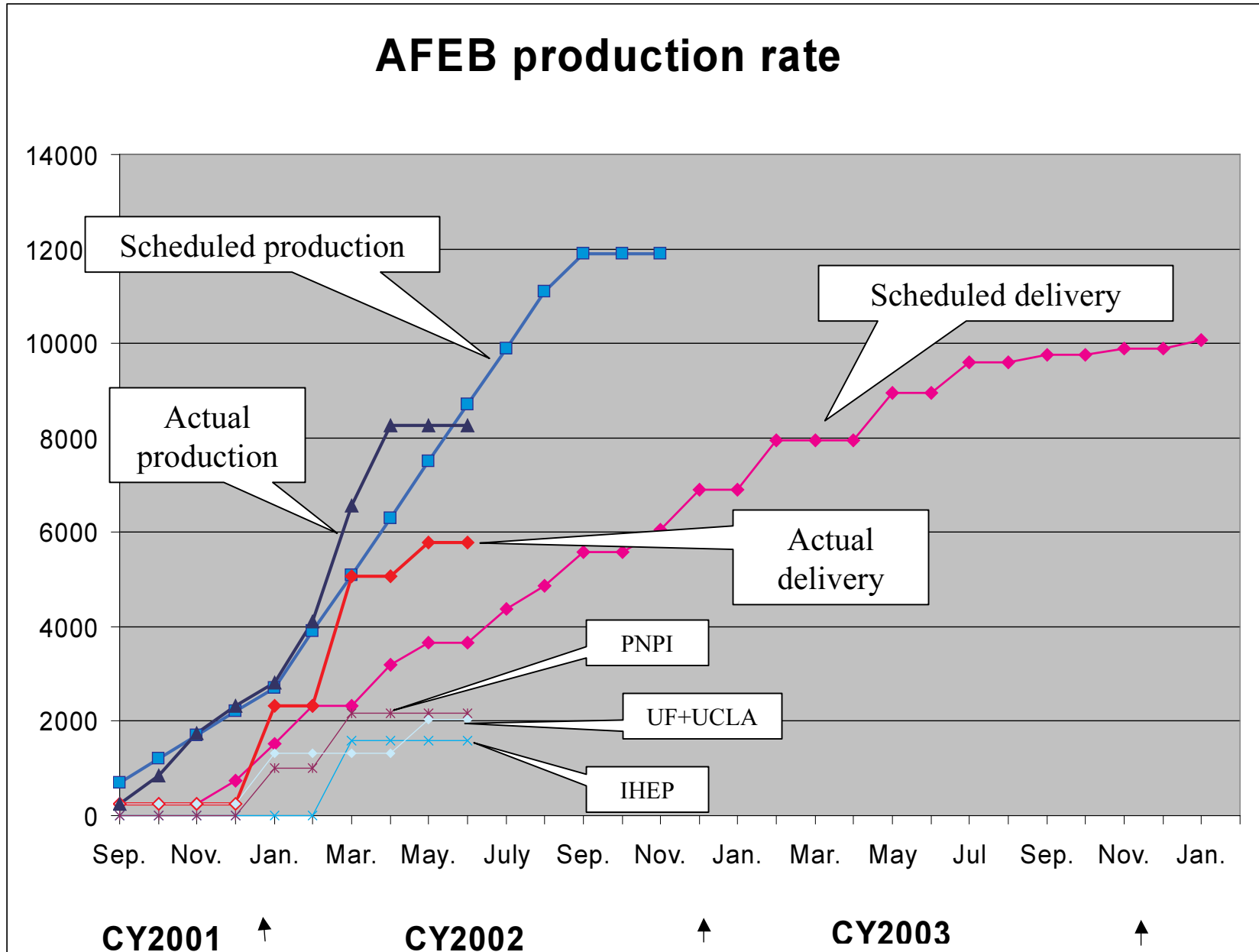
Need to produce	12,000	
Total ordered	12,200	
Total delivered to FNAL	12,200	
Certification statistic: Total measured	8600	
Total certified	8262	
Yield rate after cuts	96%	
Final yield rate (including chip selection)	~86%	

Current situation is weekly updated on the following WEB page:
<http://www-hep.phys.cmu.edu/cms/MASSPRTEST/AFEB/passmp.html>





AFEB production and shipment rate





Anode electronics assembly instructions.

The following instructions and manuals were prepared and located at the following WEB site
<http://www-hep.phys.cmu.edu/cms/> :

AFEB AD16_F user manual



Instruction for AFEB installation

Instruction for AFEB-ALCT cables installation for ME234/2 chamber

Instruction for AFEB-ALCT cables installation for ME1/2 chamber

Instruction for AFEB-ALCT cables installation for ME2/1 chamber

Instruction for AFEB-ALCT cables installation for ME3/1 chamber

Instruction for repair broken M4 thread .

Preparation in progress:



Instruction for AFEB-ALCT cables installation for ME1/3 chamber - the chamber in Lab 7.

Instruction for AFEB-ALCT cables installation for ME4/1 chamber - the chamber in Lab 7.











AFEB-ALCT cables display

Chamber type	FAST site	CY2001												CY2002						Made	Total needed	Balance	Ship.	Stored at FNAL
		Mar	Apr	May	Jun	Jul	Aug	Sep	Oct	Nov	Dec	Jan	Feb	Mar	Apr	May	Jun							
ME 234/2	deliv.	8	10	10	10				10	10	10		10	10	10				98	148	50		15	
	UF							15								12						43		
	UCLA					1	15					14				10						40		
ME1/2	deliv.	9	10	10	10				10	10	10		5						74	74	0		0	
	IHEP													74								74		
ME1/3	deliv.							1	5	9			9	10	10				44	74	30		0	
	IHEP														44							44		
ME2/1	deliv.		9	10	10				8										37	38	1		1	
	PNPI											36										36		
ME3/1	deliv.									6	6		6	8	8				34	38	4		0	
	PNPI												18		16							34		
ME4/1	deliv.	/	/	/	/	/	/	/	/	/	/	/	/	/	/	/	/	/	0	38	38	/	0	
	PNPI	/	/	/	/	/	/	/	/	/	/	/	/	/	/	/	/	/	/	/	/	0	/	

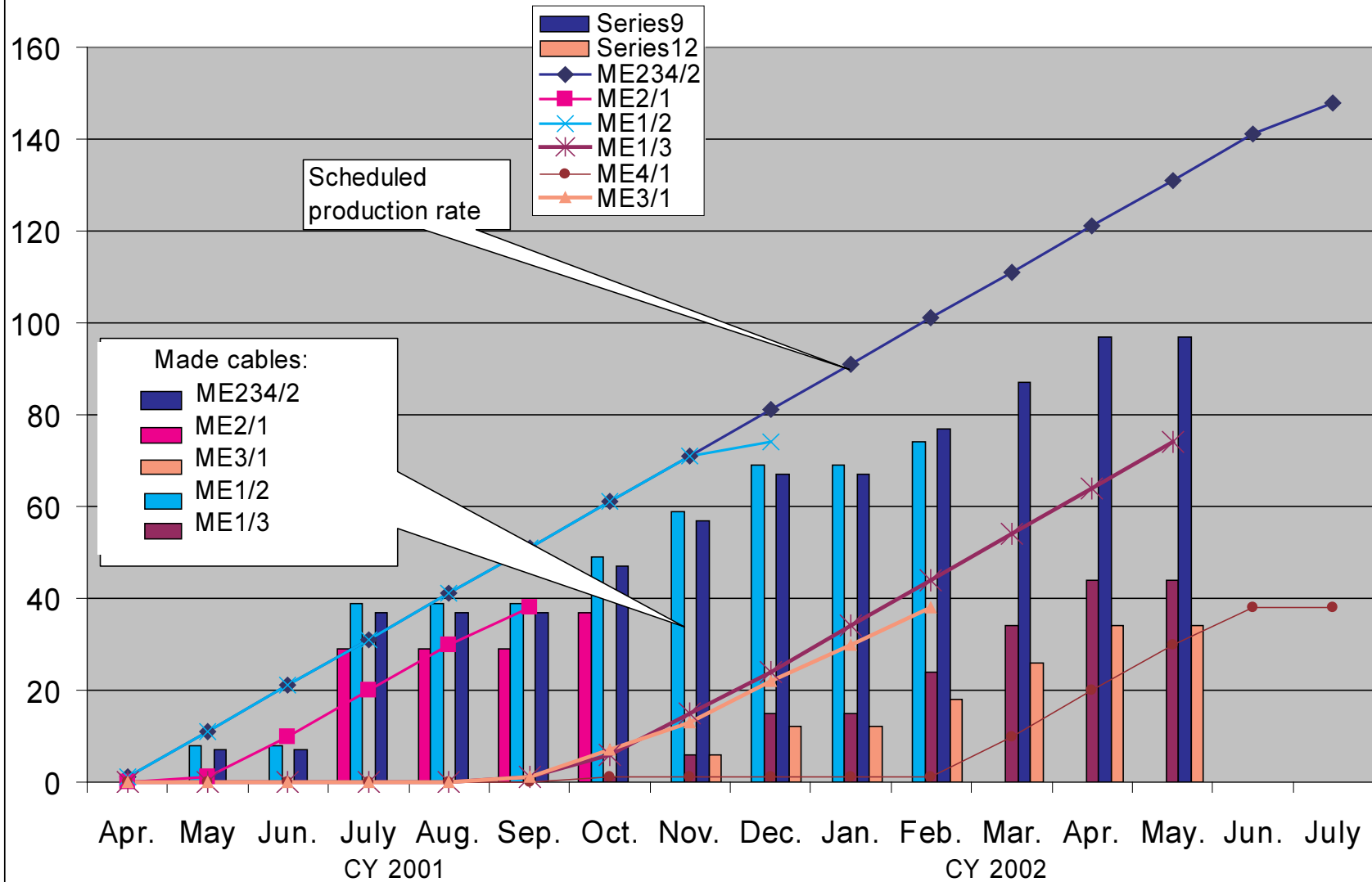
Total cables to produce - 10760
 Total produced cables - 7554
 Production balance - 3206

-  ME234/2 - 98 sets made, 83 shipped to FAST sites
-  ME2/1 - completed, shipped to PNPI.
-  ME3/1 - 34 sets made, shipment to PNPI.
-  ME1/2 - completed, shipped to IHEP
-  ME1/3 - 44 sets made, shipment to IHEP
-  ME4/1 - standby position.



AFEBA-ALCT cables display

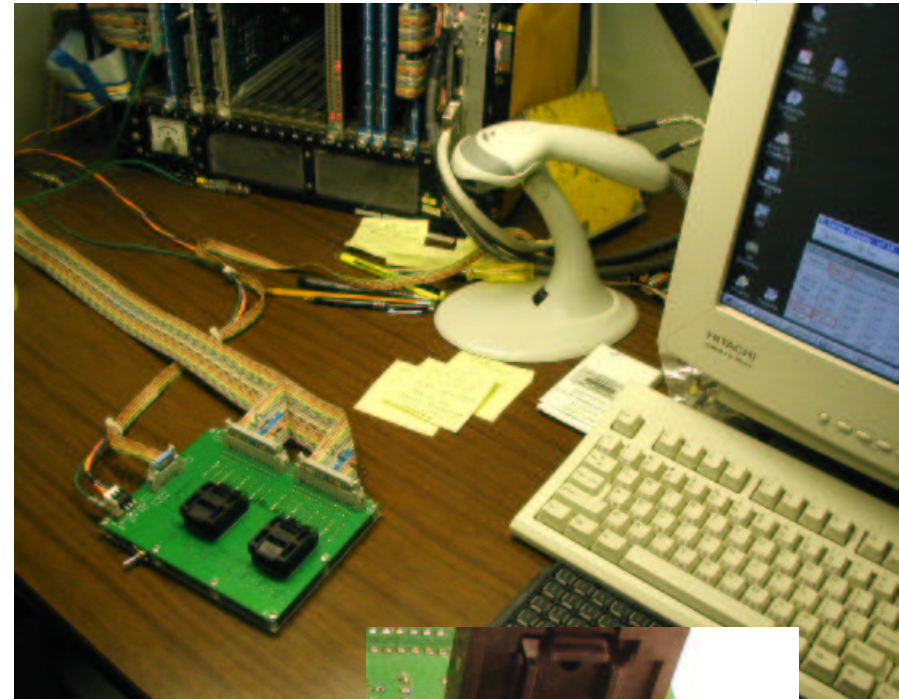
AFEBA-ALCT cable production rate





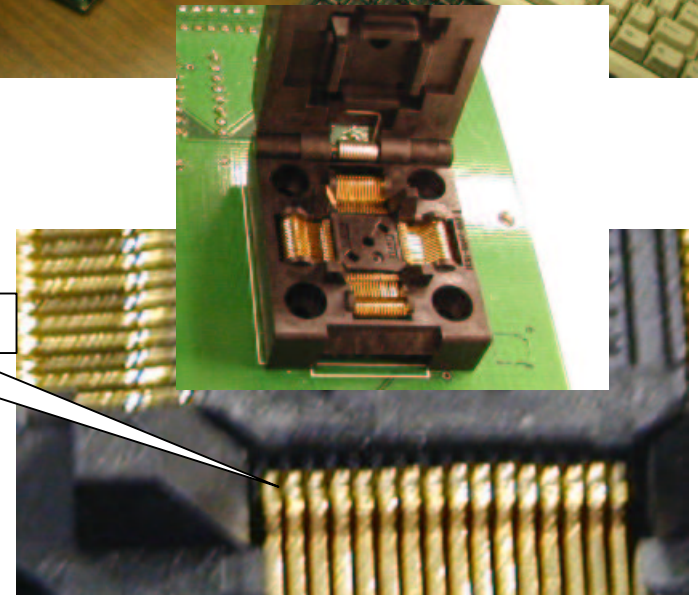
Delay chip DEL16 status.

Produced	25,000
Tested	19995
Good chips	17,138
Rejected - parameters out of nominal and dead	2,857
Yield rate (pass all cuts)	~ 86%



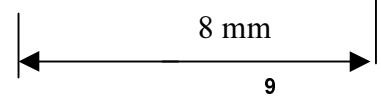
After about 1200 measured chips the adapter's clamp shell connector began to loose contacts with chips.
Reason - the gold plated surface of the connector contact degradation.
We replaced the adapter with new one.

Contact width 0.25mm



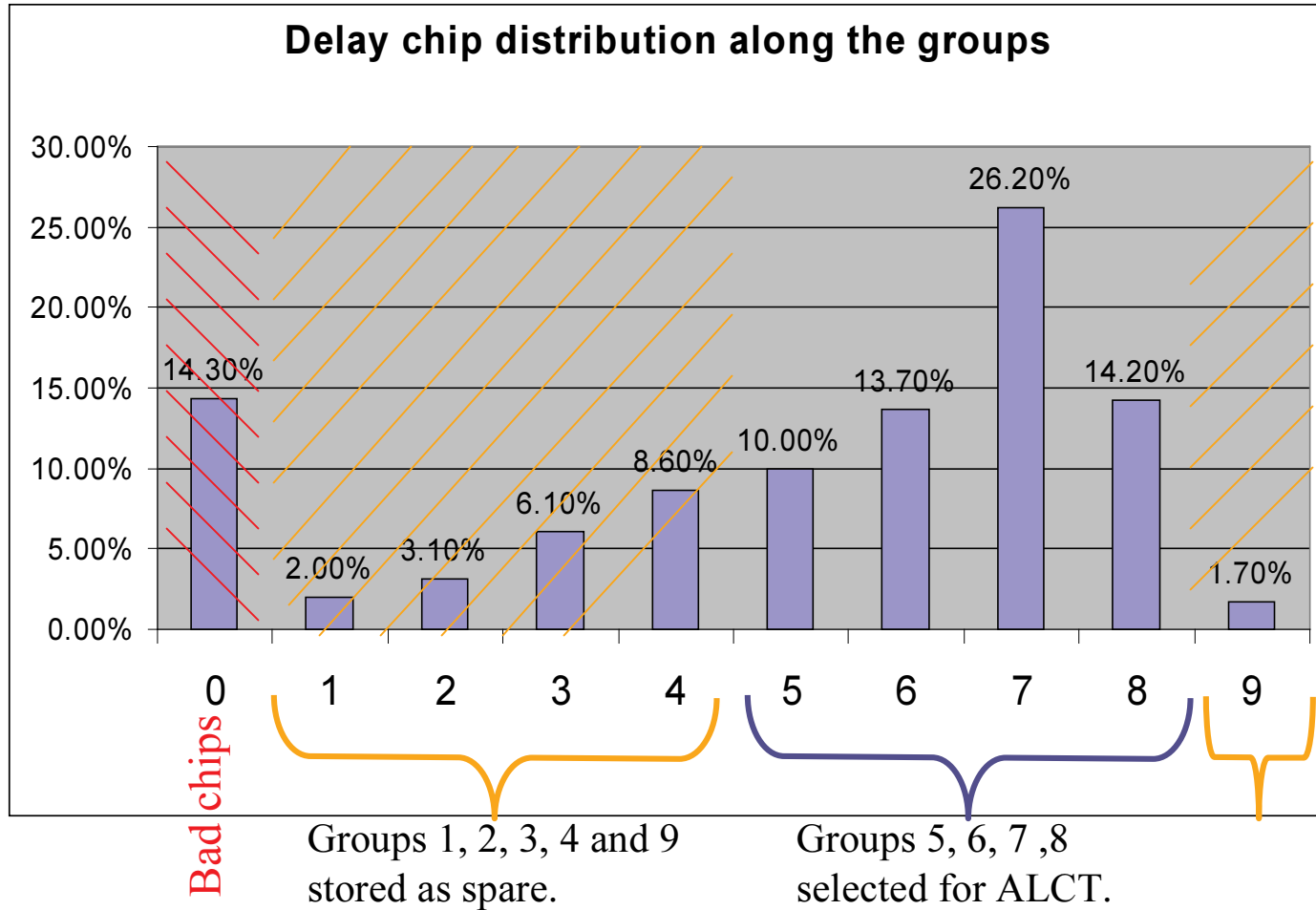
Current situation with the delay chip test is collected and weekly updated at the following WEB site:

<http://www-hep.phys.cmu.edu/cms/MASSPRTEST/D16GMP/passmp.html>.





Delay chip DEL16 status.



Expected number of good chips
 Final yield rate after selection

~15900
 ~64%



Shipped to UCLA:	Group 5	Group 6	Group 7	Group 8	Total
	1920	2240	4960	2560	1168